Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/892,312	LEE, SIEW FEI
Examiner	Art Unit
Kevin M. Nguyen	2674

SEARCHED					
Class	Subclass	Date	Examiner		
345	156	11/7/2005	KMN		
200	5A, 5R	11/7/2005	KMN		
200	11R, 314	11/7/2005	KMN		
200	336	11/7/2005	KMN		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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STRATEGY	
DATE	EXMR
11/7/2005	KMN
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